

Agilent Technologies Infiniium MSO8000 and MSO9000 Series N5433A FPGA Dynamic Probe for Altera

Data Sheet

The challenge

You rely on the insight a MSO (mixed-signal oscilloscope) provides to understand the behavior of your FPGA in the context of the surrounding system. Design engineers typically take advantage of the programmability of the FPGA to route internal nodes to a small number of physical pins for debugging. While this approach is very useful, it has significant limitations.

- Since pins on the FPGA are typically an expensive resource, there are a relatively small number available for debug. This limits internal visibility (i.e. one pin is required for each internal signal to be probed).
- When you need to access different internal signals, you must change your design to route these signals to the available pins. This can be time consuming and can affect the timing of your FPGA design.

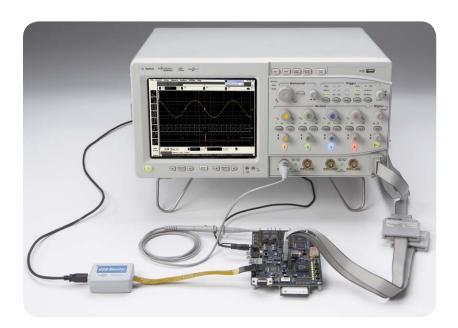


Figure 1. FPGA dynamic probe for Altera used in conjunction with an Agilent MSO provides an effective solution for simple through complex debugging of systems incorporating Altera FPGAs.

 Finally, the process required to map the signal names from your FPGA design to the MSO digital channel labels is manual and tedious.
 When new signals are routed out, you need to manually update these signal names on the MSO, which takes additional time and is a potential source of confusing errors.



Debug your FPGAs faster and more effectively with a MSO

FPGA dynamic probe lets you:

View internal activity – With the digital channels on your MSO, you are normally limited to measuring signals at the periphery of the FPGA. With the FPGA dynamic probe, you can now access signals internal to the FPGA. You can measure up to 256 internal signals for each external pin dedicated to debug, unlocking visibility into your design that you never had before.

Make multiple measurements in seconds – Moving probe points internal to an FPGA used to be time consuming. Now, in less than a second, you can easily measure different sets of internal signals without design changes. FPGA timing stays constant when you select new sets of internal signals for probing.

Leverage the work you did in your design environment – The FPGA dynamic probe maps internal signal names from your FPGA design tool to your Agilent MSO. Eliminate unintentional mistakes and save hours of time with this automatic setup of signal and bus names on your MSO.

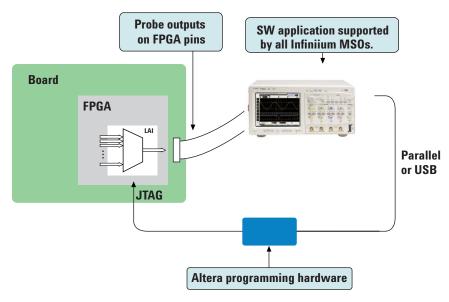


Figure 2. The FPGA dynamic probe requires Altera's Quartus II design software with its LAI (logic analyzer interface) and Altera programming hardware setup. The Quartus II (ver. 6.0 or higher) LAI allows you to create and insert a debug core that interacts with the FPGA dynamic probe application on your MSO. The FPGA dynamic probe controls which group of internal signals to measure via the Altera programming hardware connected to the JTAG port of the FPGA.

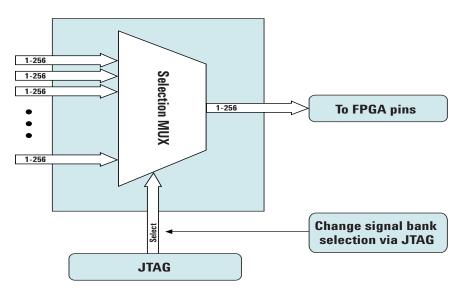
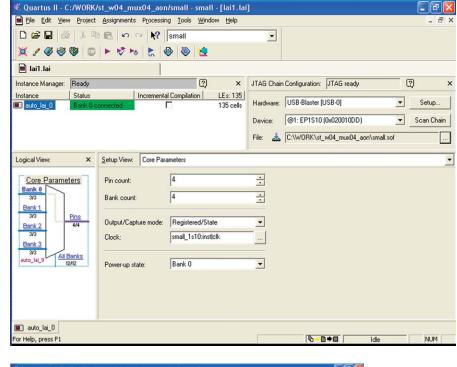


Figure 3: Access up to 256 internal signals for each debug pin. Signal banks all have identical width (1 to 256 signals wide) determined by the number of device pins you devote for debug. MS08000 series can acquire up to 16 signals using digital channels. Each pin provides sequential access to one signal from every input bank.

A quick tour of the application

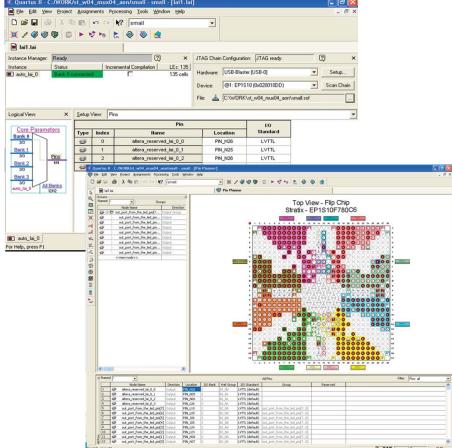
Design step 1: Configure the logic analyzer interface file and core parameters

You need to create a Altera LAI file with MSO in Quartus II. This file defines the interface that builds a connection between the internal FPGA signals and the MSO digital channels. You can then configure the core parameters, which include number of pins, number of signal banks, the type of measurement (state or timing), clock and the power-up state.



Design step 2: Map the Altera LAI core outputs to available I/O pins

Use Pin Planner in Quartus II to assign physical pin locations for the LAI.

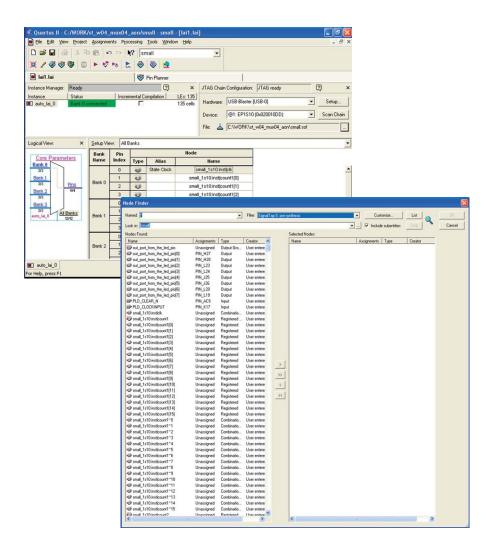


A quick tour of the application (continued)

Design step 3: Assign LAI bank parameters

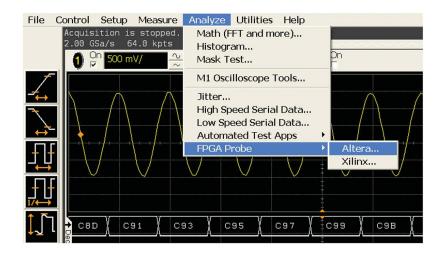
Assign internal signals to each bank in the LAI after you have specified the number of banks to use in the core parameters. Find the signals you want to acquire with the Node Finder and assign them to the banks.

With the LAI core fully configured and instantiated into your FPGA design, you're ready to compile your design to create the device programming file (.sof). Then, to make measurements you'll move to the Agilent MSO with FPGA dynamic probe software.



Activate FPGA dynamic probe for Altera

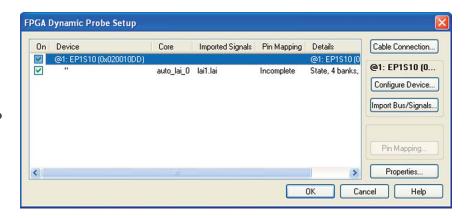
The FPGA dynamic probe application allows you to control the LAI and set up the MSO for the desired measurements.



A quick tour of the application (continued)

Measurement setup step 1: Establish a connection between the MSO and the LAI

The FPGA dynamic probe application establishes a connection between the MSO and the FPGA via a JTAG cable. It also determines what devices are on the JTAG scan chain and lets you pick the one with which you wish to communicate.



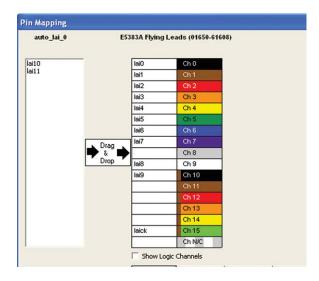
Measurement setup step 2: Configure the device and import signal names

If needed, you can configure the device with the SRAM object file (.sof) that includes the logic analyzer interface file. The FPGA dynamic probe application reads a .lai file produced by Quartus II. The names of signals you measure will now automatically appear in the label names on your Agilent MSO.



Measurement setup step 3: Map FPGA pins

Select your probe type and easily provide the information needed for the MSO to automatically track names of signals routed through the LAI file.



A quick tour of the application (continued)

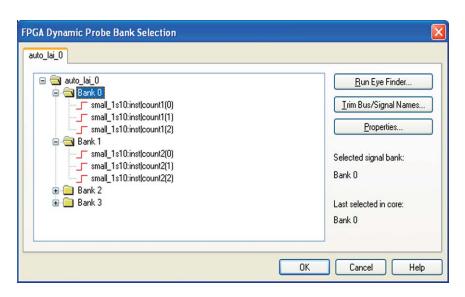
Setup complete: Make measurements Quickly change which signal bank is routed to the MSO. A single mouse click tells the LAI core to switch to the newly specified signal bank without any impact to the timing of your design. To make measurements throughout your FPGA, change signal banks as often as needed. With each new selection of a signal bank, FPGA Dynamic Probe updates new signal names from your design to the MSO. User-definable signal bank names make it straight forward to select a part of your design to measure.

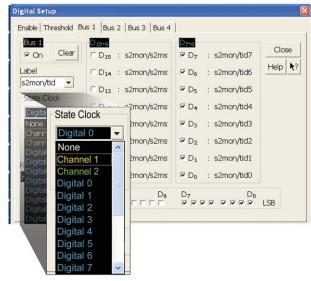
Make state measurements with your MS0

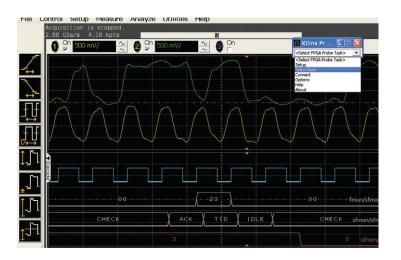
MSOs incorporate some logic analysis state capabilities useful for making FPGA measurements. Using pattern trigger, setup a state trigger on LAI clock output edge and desired digital pattern. After acquiring the data, use the post-processing "State clock" feature to transform the timing waveforms into state waveforms. Valid states are shown and invalid states are filtered. Any of the 16 digital channels or any of the analog channels can be set as the state clock. Using an analog channel state clock allows you to retain all 16 digital channels for bus measurement.

Correlate internal FPGA activity with external measurements

View internal FPGA activity and time-correlate internal FPGA measurements with external analog and digital events in the surrounding system. FPGA Dynamic Probe unlocks the power of the MSO for system-level debug with FPGAs.







Agilent N5433A specifications and characteristics

Supported oscilloscopes

Standalone oscilloscopes	All Infiniium 8000 and 9000 Series MSOs.	
MSO Digital Channels	16	
Bus groupings	Up to 4, each with 16 character labels	
Triggering capabilities	Determined by MSO, all have state triggering	
Supported Altera FPGA families	All families that the Altera LAI core supports including, Stratix IV, Stratix III, Stratix II and Stratix, Cyclone III, Cyclone II and Cyclone, Arria II and Arria.	
Supported Altera cables (required)	Altera USB Blaster or ByteBlaster	
Supported probing mechanisms	Soft touch (34-channel and 17-channel), Mictor, Samtec, Flying lead, Infiniium MSOs come standard with a 40 pin probe cable and flying leads.	
Altera LAI characteristics		
Number of output signals	User definable: 1 to 256 signals in 1 signal increments. MSO can measure maximum of 16 digital channels	
Signal banks	User definable: 1 to 256 banks	
Modes	State (synchronous) or timing (asynchronous) mode	
Compatible software		
Altera Quartus II 6.0 or greater	Infiniium 8000 version 5.2 or greater. Infiniium 9000 version 2.0 or greater.	

Additional information available via the Internet www.agilent.com/find/8000-altera

Ordering information

Ordering options for the Agilent N5433A FPGA dynamic probe for Altera

Option 001	Entitlement certificate for perpetual node-locked license locked to oscilloscope (most common license type)
Option 002	Entitlement certificate for PC locked license. PC and MSO must both connect to LAN. (less common license type)

Related literature

Publication title	Publication type	Publication number
Frequently Asked Questions for Agilent MSO FPGA Dynamic Probe for Altera	Data sheet	5989-5957EN
Agilent Technologies Infiniium 8000 series Oscilloscopes	Color brochure	5989-4271EN
Infiniium 9000 Series Oscilloscopes	Data sheet	5989-3746EN

Product Web site

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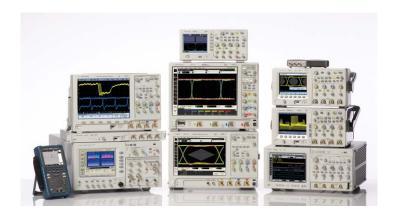
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